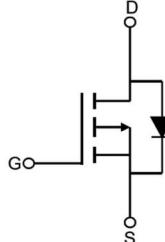


Description

<p>Features</p> <ul style="list-style-type: none"> ● $V_{DS} = -40V$, $I_D = -6A$ $R_{DS(ON)} < 47m\Omega @ V_{GS} = -10V$ $R_{DS(ON)} < 66m\Omega @ V_{GS} = -4.5V$ ● Advanced Trench Technology ● Excellent $R_{DS(ON)}$ and Low Gate Charge ● Lead free product is acquired 	<p>Application</p> <ul style="list-style-type: none"> ● PWM Applications ● Load Switch ● Power Management <p>100% UIS 100% ΔV_{ds}</p>
 SOP-8	 Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
VSM6P04-S8	VSM6P04	TAPING	SOP-8	13inch	4000	48000

Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		-40	V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Continuous Drain Current	$T_A = 25^\circ C$	-6	A
		$T_A = 100^\circ C$	-4	A
I_{DM}	Pulsed Drain Current ^{note1}		-24	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		27.6	mJ
P_D	Power Dissipation	$T_A = 25^\circ C$	3	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient		41.7	$^\circ C/W$
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D = -250\mu\text{A}$	-40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -40\text{V}$, $V_{GS}=0\text{V}$	-	-	-1	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}$, $V_{GS}= \pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D = -250\mu\text{A}$	-1.0	-1.5	-2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS} = -10\text{V}$, $I_D = -6\text{A}$	-	36	47	$\text{m}\Omega$
		$V_{GS} = -4.5\text{V}$, $I_D = -4\text{A}$	-	47	66	
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = -20\text{V}$, $V_{GS}=0\text{V}$, $f=1.0\text{MHz}$	-	1034	-	pF
C_{oss}	Output Capacitance		-	107	-	pF
C_{rss}	Reverse Transfer Capacitance		-	79.5	-	pF
Q_g	Total Gate Charge	$V_{DS} = -20\text{V}$, $I_D = -3\text{A}$, $V_{GS} = -10\text{V}$	-	20	-	nC
Q_{gs}	Gate-Source Charge		-	3.5	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	4.2	-	nC
Switching Characteristics						
$t_{d(\text{on})}$	Turn-on Delay Time	$V_{DD} = -20\text{V}$, $I_D = -6\text{A}$, $V_{GS} = -10\text{V}$, $R_{\text{GEN}}=2.5\Omega$	-	8	-	ns
t_r	Turn-on Rise Time		-	15	-	ns
$t_{d(\text{off})}$	Turn-off Delay Time		-	23	-	ns
t_f	Turn-off Fall Time		-	9	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current	-	-	-10	-	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	-40	-	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_S = -6\text{A}$	-	-0.8	-1.2	V
trr	Reverse Recovery Time	$V_{GS}=0\text{V}$, $I_S = -5\text{A}$,	-	29	-	ns
		di/dt=100A/ μs	-	20	-	nC

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition: $T_J= 25^\circ\text{C}$, $V_{DD} = -20\text{V}$, $V_G = -10\text{V}$, $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = -10.5\text{A}$

3. Pulse Test: Pulse Width≤300 μs , Duty Cycle≤2%

Typical Performance Characteristics

Figure1: Output Characteristics

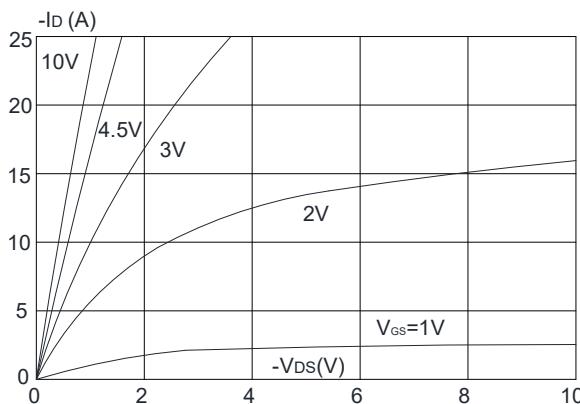


Figure 3: On-resistance vs. Drain Current

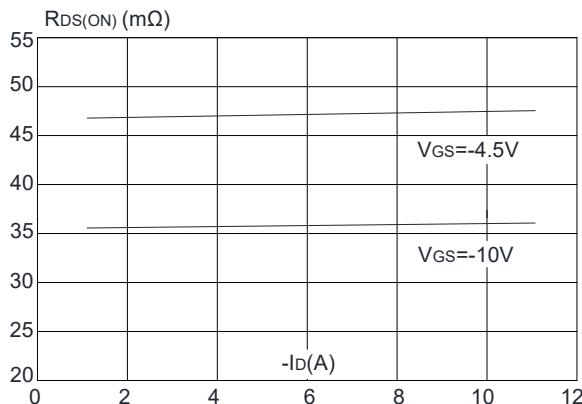


Figure 5: Gate Charge Characteristics

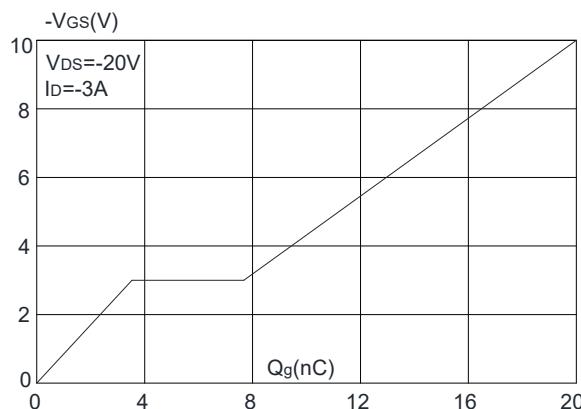


Figure 2: Typical Transfer Characteristics

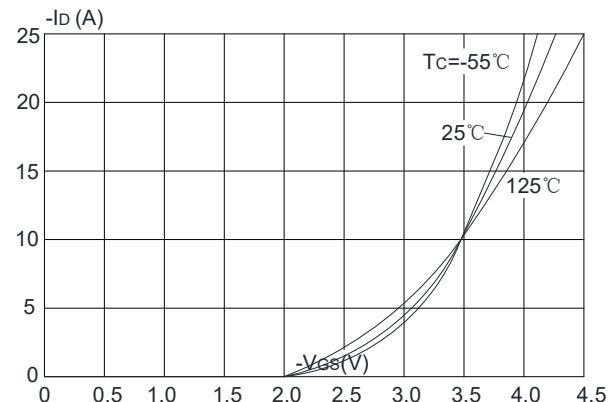


Figure 4: Body Diode Characteristics

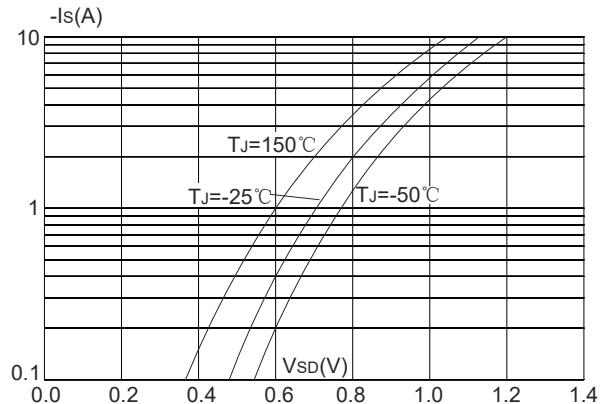


Figure 6: Capacitance Characteristics

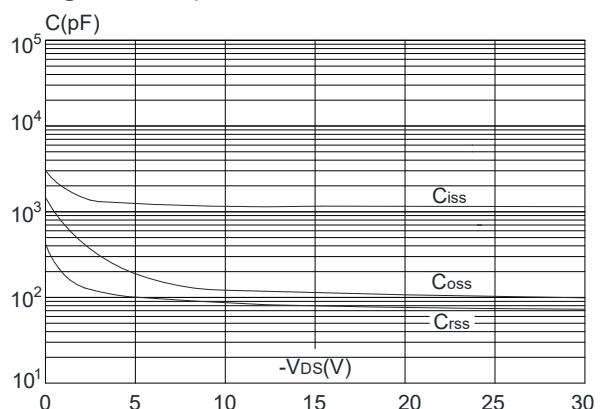


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

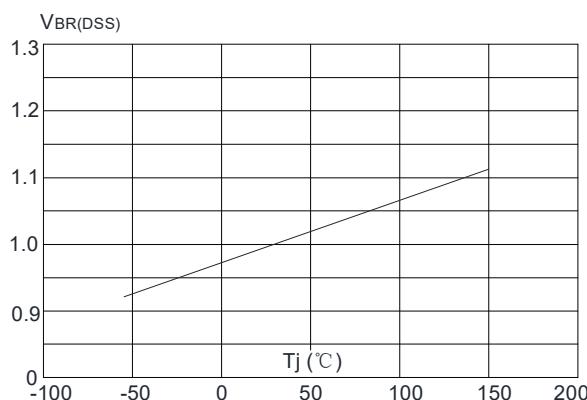


Figure 8: Normalized on Resistance vs. Junction Temperature

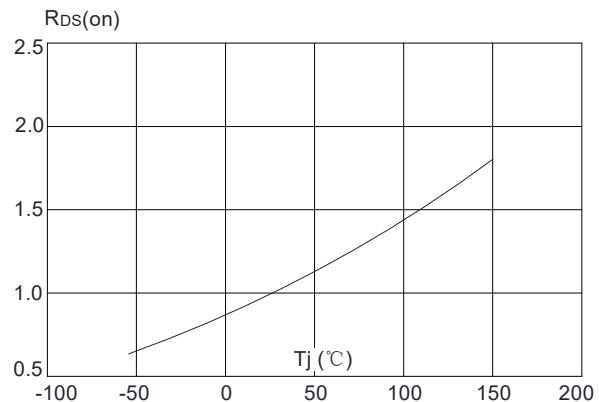


Figure 9: Maximum Safe Operating Area

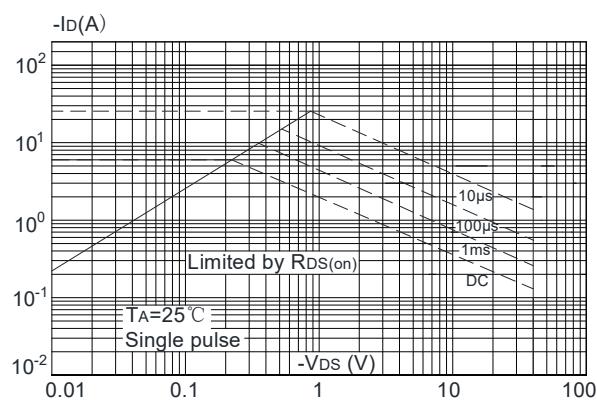


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

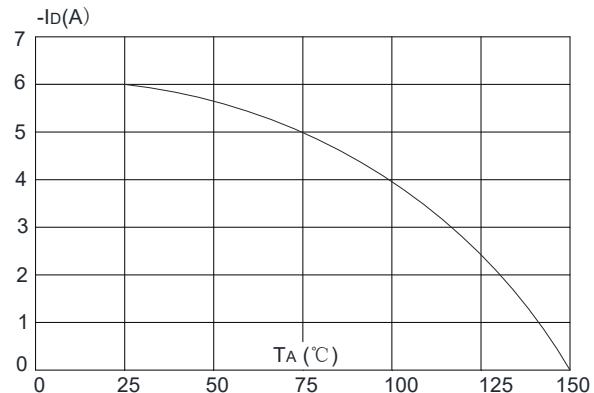
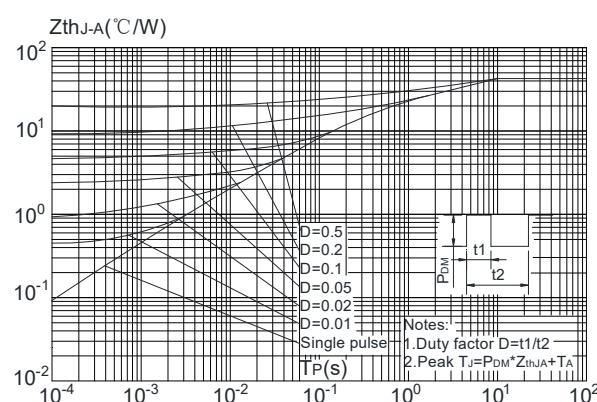
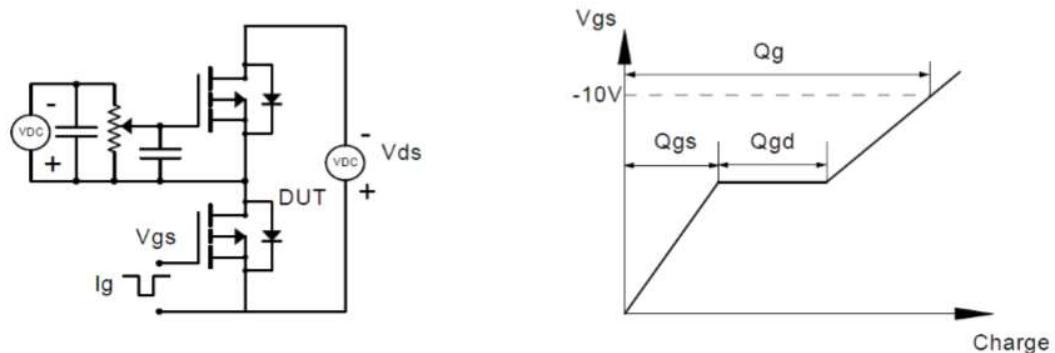


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

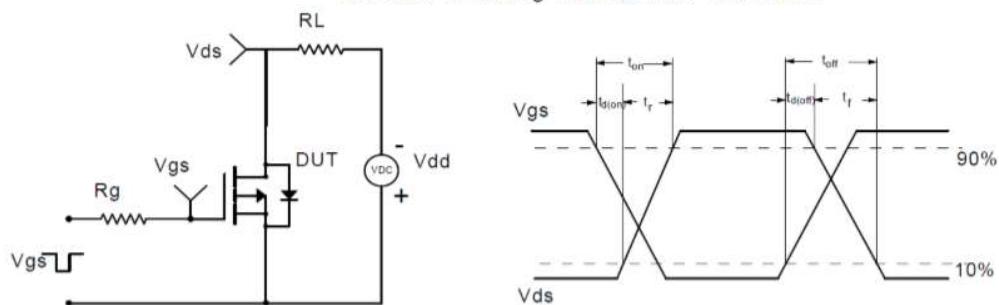


Test Circuit

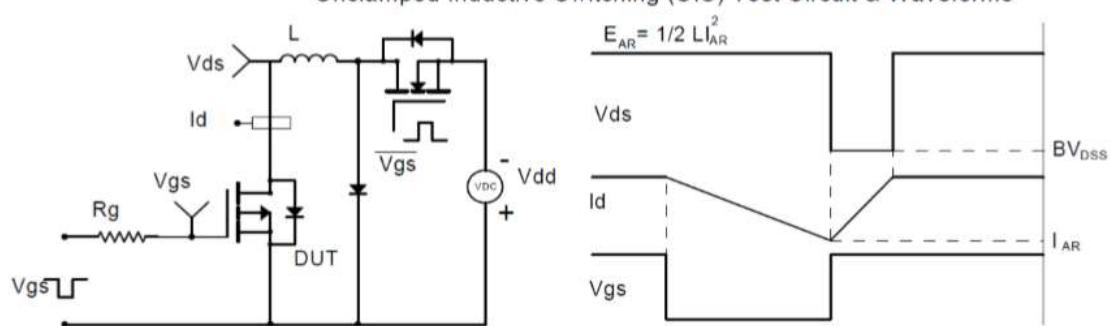
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

